

Supporting Information

Optimization and Device Application Potential of Oxide-Metal-Oxide Transparent Electrode Structure

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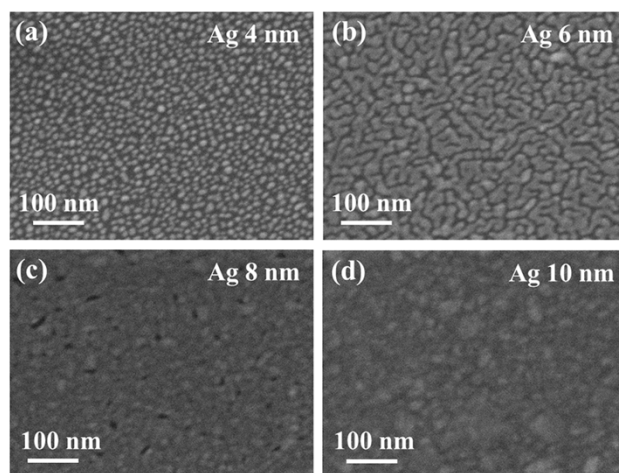


Fig. S1 SEM micrographs showing the morphological evolution of the Ag mid-layer with increasing thickness.

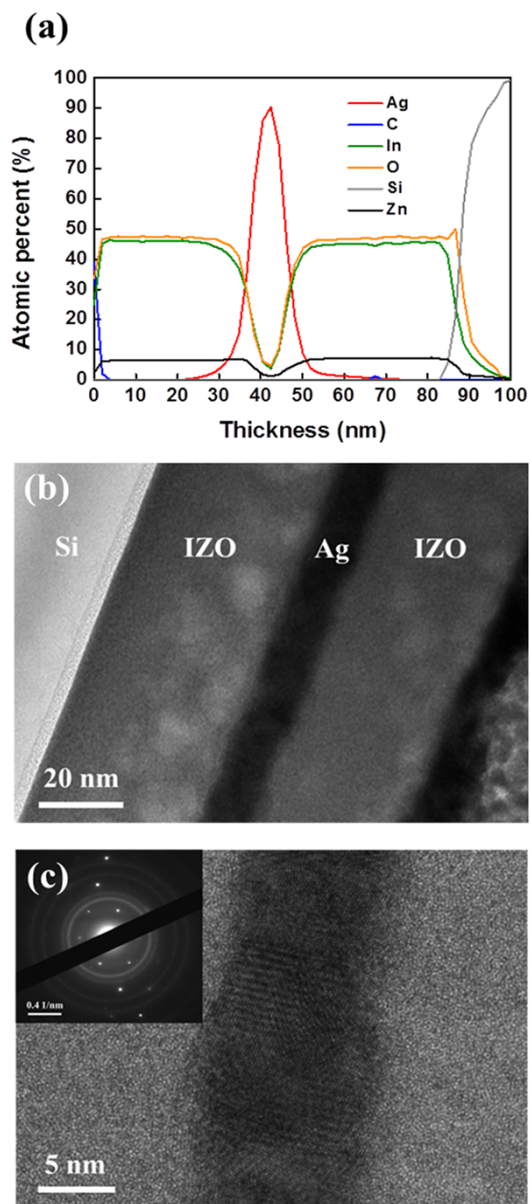


Fig. S2 Cross-sectional structure of the optimized IZO-Ag-IZO electrode as identified by: (a) XPS depth profile, (b) cross-sectional TEM (JSM-2100F, JEOL) contrast image, and (c) HRTEM image. It is seen that top and bottom IZO layers (amorphous) and Ag mid-layer (polycrystalline) are well defined with compositional uniformity and smooth interfaces.